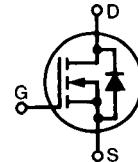


HiPerFET™ Power MOSFETs

N-Channel Enhancement Mode
High dv/dt, Low t_{rr} , HDMOS™ Family

IXFH14N80
IXFH15N80

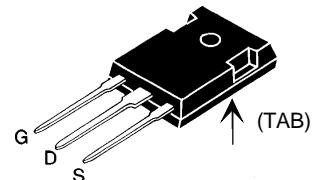
V_{DSS}	I_{D25}	$R_{DS(on)}$
800 V	14 A	0.70 Ω
800 V	15 A	0.60 Ω
$t_{rr} \leq 250 \text{ ns}$		



Preliminary data

Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ\text{C}$ to 150°C	800	V	
V_{DGR}	$T_J = 25^\circ\text{C}$ to 150°C ; $R_{GS} = 1 \text{ M}\Omega$	800	V	
V_{GS}	Continuous	± 20	V	
V_{GSM}	Transient	± 30	V	
I_{D25}	$T_c = 25^\circ\text{C}$	14N80 15N80	14 15	A
I_{DM}	$T_c = 25^\circ\text{C}$, pulse width limited by T_{JM}	14N80 15N80	56 60	A
I_{AR}	$T_c = 25^\circ\text{C}$	14N80 15N80	14 15	A
E_{AR}	$T_c = 25^\circ\text{C}$		30	mJ
dv/dt	$I_s \leq I_{DM}$, $di/dt \leq 100 \text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ\text{C}$, $R_G = 2 \Omega$		5	V/ns
P_D	$T_c = 25^\circ\text{C}$	300		W
T_J		-55 ... +150		°C
T_{JM}		150		°C
T_{stg}		-55 ... +150		°C
T_L	1.6 mm (0.062 in.) from case for 10 s	300		°C
M_d	Mounting torque	1.13/10	Nm/lb.in.	
Weight		6		g

TO-247 AD



G = Gate
S = Source
D = Drain
TAB = Drain

Features

- International standard packages
- Low $R_{DS(on)}$ HDMOS™ process
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
 - easy to drive and to protect
- Fast intrinsic Rectifier

Applications

- DC-DC converters
- Synchronous rectification
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- AC motor control
- Temperature and lighting controls
- Low voltage relays

Advantages

- Easy to mount with 1 screw (isolated mounting screw hole)
- Space savings
- High power density

Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
V_{DSS}	$V_{GS} = 0 \text{ V}$, $I_D = 3 \text{ mA}$ V_{DSS} temperature coefficient	800	0.096	V %/K
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 4 \text{ mA}$ $V_{GS(th)}$ temperature coefficient	2.0	-0.214	V %/K
I_{GSS}	$V_{GS} = \pm 20 \text{ V}_{DC}$, $V_{DS} = 0$			± 100 nA
I_{DSS}	$V_{DS} = 0.8 V_{DSS}$ $V_{GS} = 0 \text{ V}$	$T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$		250 μA 1 mA
$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$, $I_D = 0.5 I_{D25}$ Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2 \%$	14N80 15N80		0.70 Ω 0.60 Ω

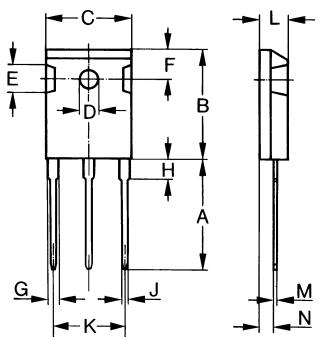
Symbol	Test Conditions	Characteristic Values			
		(T _j = 25°C, unless otherwise specified)	Min.	Typ.	Max.
g_{fs}	$V_{DS} = 10 \text{ V}; I_D = 0.5 I_{D25}$, pulse test	8	14	S	
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	3965	4870	pF	
		315	395	pF	
		73	120	pF	
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = 0.5 I_{D25}$ $R_G = 2 \Omega$ (External)	20	50	ns	
		33	50	ns	
		63	100	ns	
		32	50	ns	
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = 0.5 I_{D25}$	128	155	nC	
		30	45	nC	
		55	80	nC	
R_{thJC}			0.42	K/W	
R_{thCK}		0.25		K/W	

Source-Drain Diode

Characteristic Values
(T_j = 25°C, unless otherwise specified)

Symbol	Test Conditions	min.	typ.	max.
I_s	$V_{GS} = 0 \text{ V}$	14N80		14 A
		15N80		15 A
I_{SM}	Repetitive;	14N80		56 A
		15N80		60 A
V_{SD}	$I_F = I_s, V_{GS} = 0 \text{ V},$ Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2 \%$		1.5	V
t_{rr} Q_{RM} I_{RM}	$I_F = I_s$ $-di/dt = 100 \text{ A}/\mu\text{s},$ $V_R = 100 \text{ V}$	$T_j = 25^\circ\text{C}$	250	ns
		$T_j = 125^\circ\text{C}$	400	ns
			1	μC
			8.5	A

TO-247 AD Outline



Dim.	Millimeter Min.	Millimeter Max.	Inches Min.	Inches Max.
A	19.81	20.32	0.780	0.800
B	20.80	21.46	0.819	0.845
C	15.75	16.26	0.610	0.640
D	3.55	3.65	0.140	0.144
E	4.32	5.49	0.170	0.216
F	5.4	6.2	0.212	0.244
G	1.65	2.13	0.065	0.084
H	-	4.5	-	0.177
J	1.0	1.4	0.040	0.055
K	10.8	11.0	0.426	0.433
L	4.7	5.3	0.185	0.209
M	0.4	0.8	0.016	0.031
N	1.5	2.49	0.087	0.102

Figure 1. Output Characteristics at 25°C

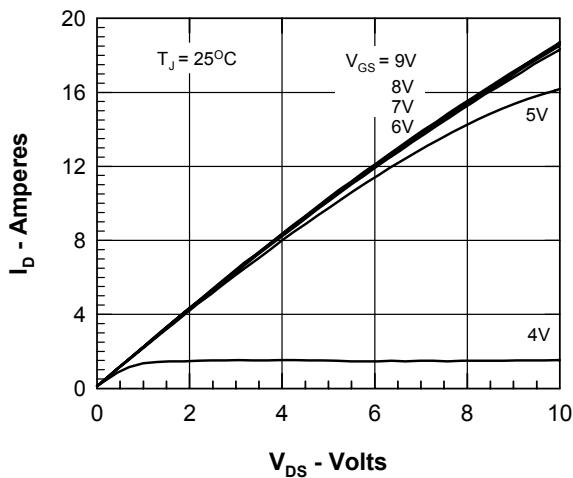


Figure 3. $R_{DS(on)}$ normalized to 0.5 I_{D25} value vs. I_D

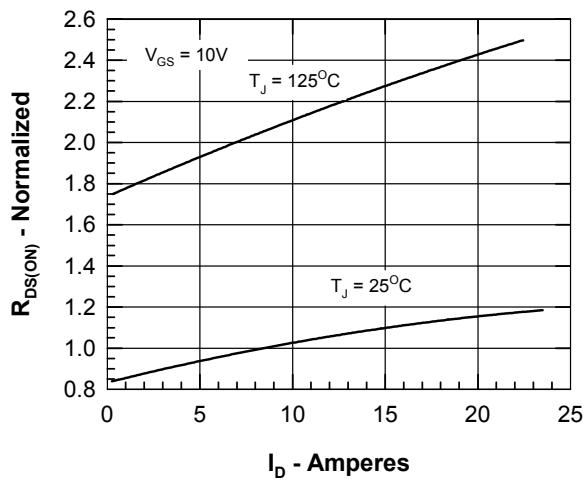


Figure 5. Drain Current vs. Case Temperature

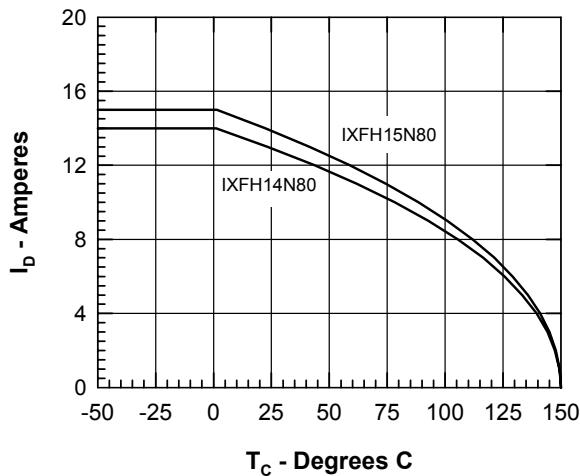


Figure 2. Output Characteristics at 125°C

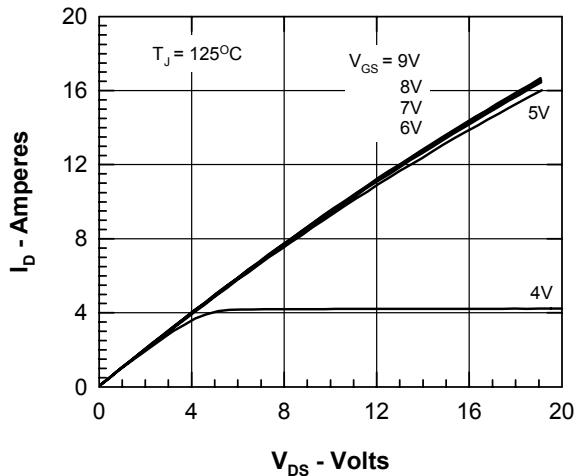


Figure 4. $R_{DS(on)}$ normalized to 0.5 I_{D25} value vs. T_J

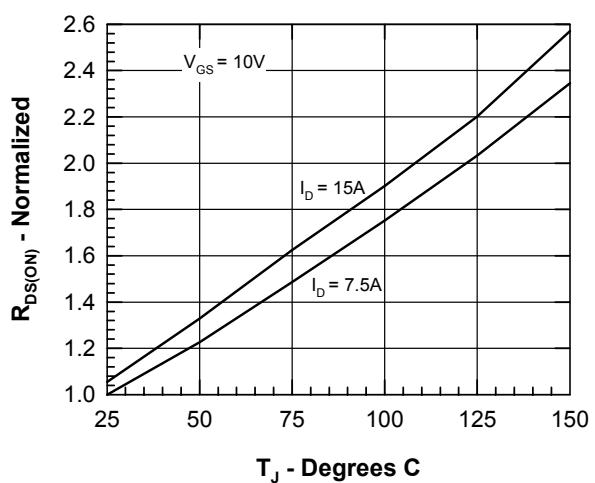


Figure 6. Admittance Curves

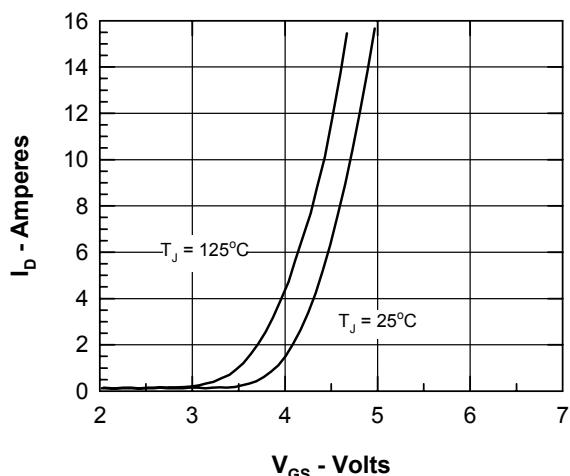


Figure 7. Gate Charge

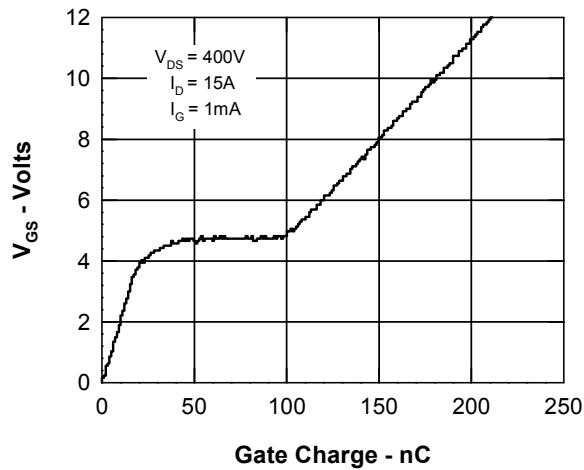


Figure 9. Source Current vs. Source to Drain Voltage

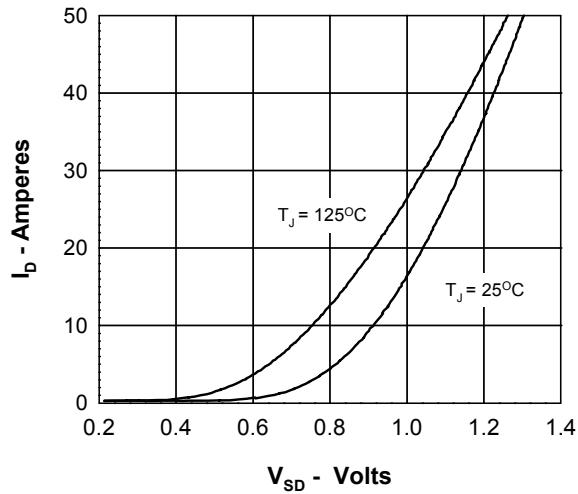


Figure 11. Transient Thermal Resistance

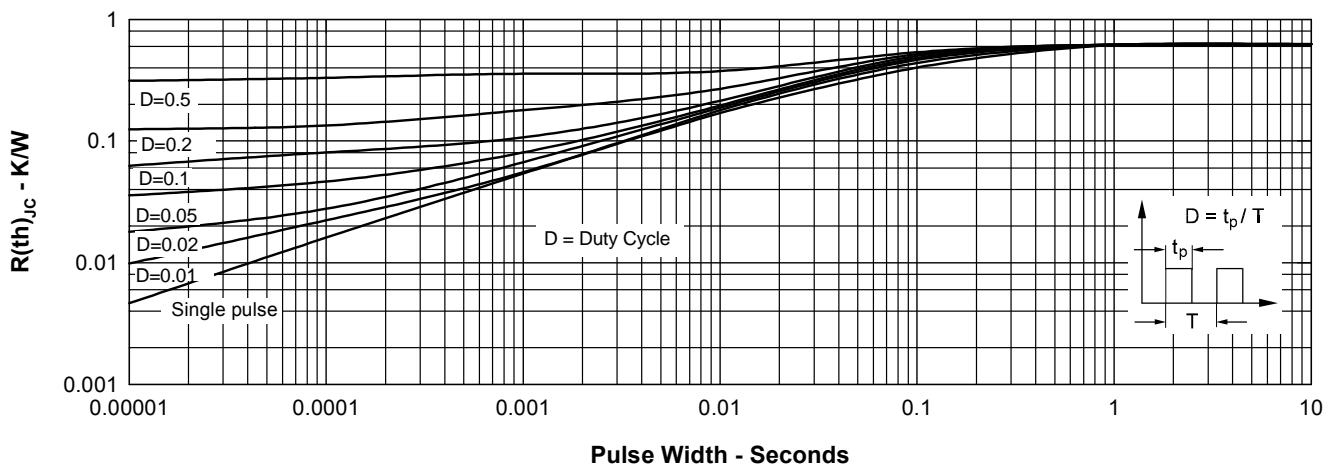


Figure 8. Capacitance Curves

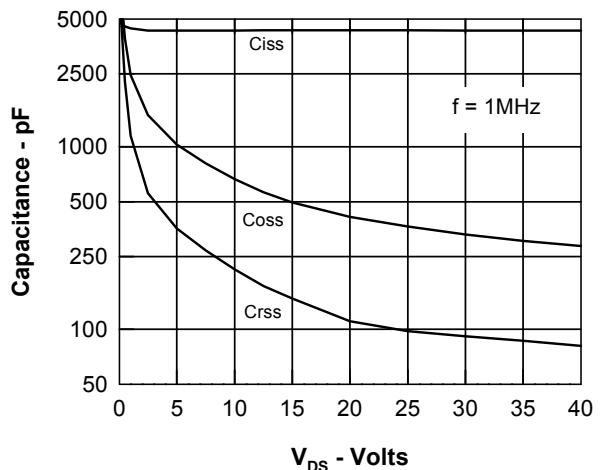


Figure 10. Forward Bias Safe Operating Area

